N-channel TrenchMOS standard level FET Rev. 01 — 23 March 2009

**Product data sheet** 

#### **Product profile** 1.

Table 1.

#### 1.1 General description

Standard level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in high performance automotive applications.

#### 1.2 Features and benefits

- AEC Q101 compliant
- Avalanche robust

- Suitable for standard level gate drive
- Suitable for thermally demanding environment up to 175°C rating

#### 1.3 Applications

**Quick reference** 

- 12V Motor, lamp and solenoid loads
- High performance automotive power systems

### 1.4 Quick reference data

High performance Pulse Width Modulation (PWM) applications

	QUICK TETETETICE						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1;</u> see <u>Figure 3;</u>	[1]	-	-	75	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	157	W
Avalanc	he ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\begin{split} I_D = 75 \text{ A};  \text{V}_{\text{sup}} \leq 40  \text{V};  \text{R}_{\text{GS}} = 50  \Omega;  \text{V}_{\text{GS}} = 10  \text{V}; \\ \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped} \end{split}$		-	-	240	mJ
Dynamic	characteristics						
Q <sub>GD</sub>	gate-drain charge	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \text{ V}_{DS} = 32 \text{ V}; \text{ T}_{j} = 25 \ ^{\circ}\text{C}; \\ \text{see } \underline{\text{Figure 15}} \end{array}$		-	27	-	nC
Static ch	naracteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>		-	4.1	5	mΩ

[1] Current is limited by package.



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## 2. Pinning information

Table 2.	Pinning	information				
Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	G	gate		_		
2	D	drain	mb			
3	S	source				
mb	D	mounting base; connected to drain		mbb076 S		
			SOT428 (SC-63; DPAK)			

## 3. Ordering information

Table 3. Ordering information							
Type number	Package						
	Name	Description	Version				
BUK725R0-40C	SC-63; DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428				

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### 4. Limiting values

#### Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>DGR</sub>	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	40	V
V <sub>GS</sub>	gate-source voltage			-20	20	V
ID	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u> ;	[1]	-	75	А
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u>	[1]	-	75	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; $t_p \le 10 \ \mu$ s; pulsed; see <u>Figure 3</u>		-	490	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	157	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dr	ain diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C;	[2]	-	75	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	490	А
Avalanche	ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$    I_D = 75 \text{ A};  \text{V}_{\text{sup}} \leq 40 \text{ V};  \text{R}_{\text{GS}} = 50  \Omega;  \text{V}_{\text{GS}} = 10 \text{ V}; \\ \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped} $		-	240	mJ
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	see Figure 4	[3][4] [5]	-	-	J

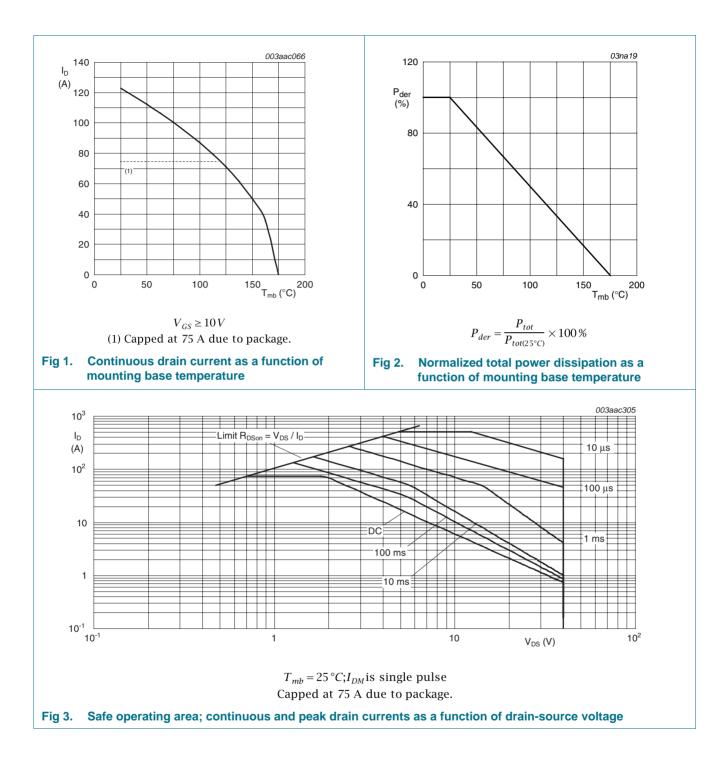
[1] Current is limited by package.

[2] Continuous current is limited by package.

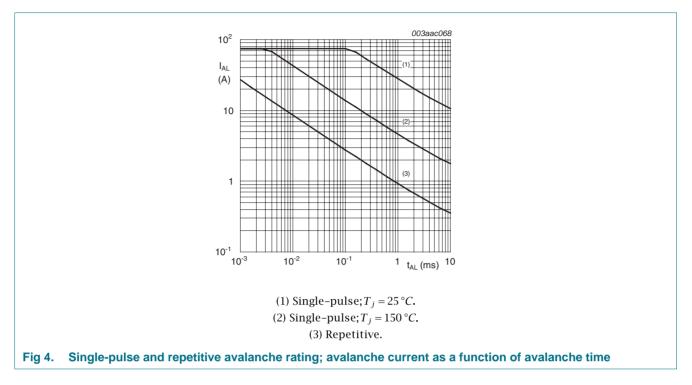
[3] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[4] Repetitive avalanche rating limited by average junction temperature of 170 °C.

[5] Refer to application note AN10273 for further information.



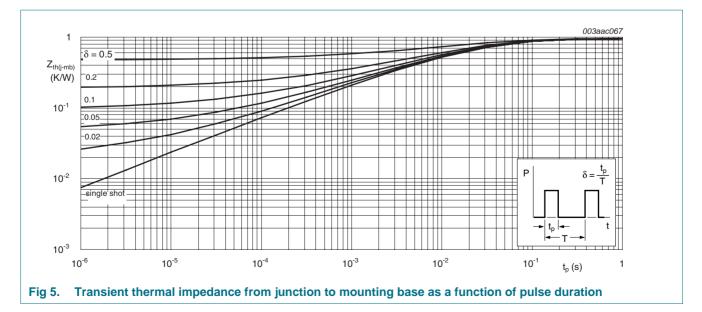
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### 5. Thermal characteristics

#### Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 5	-	0.65	0.95	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in still air; mounted on a printed circuit board; minimum foot-print	-	70	-	K/W

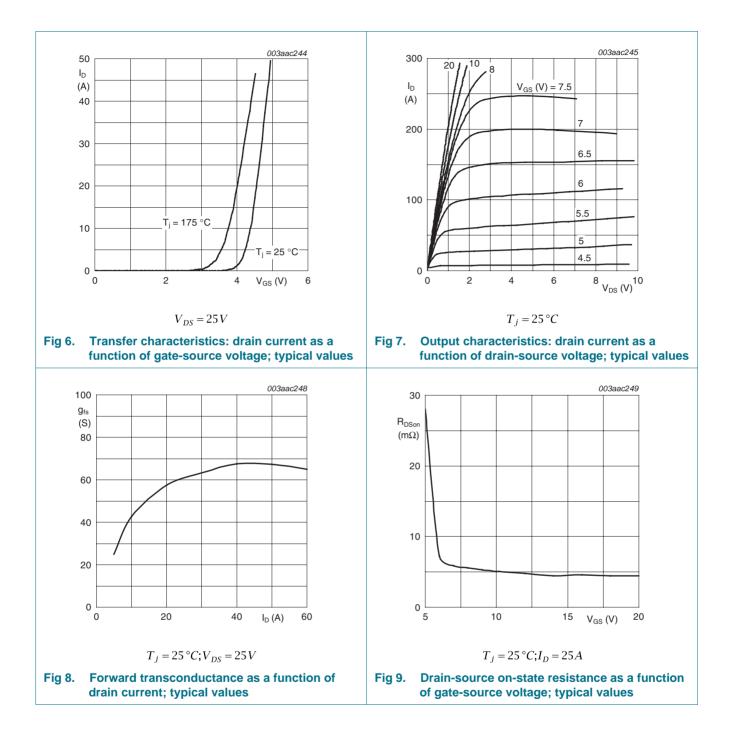


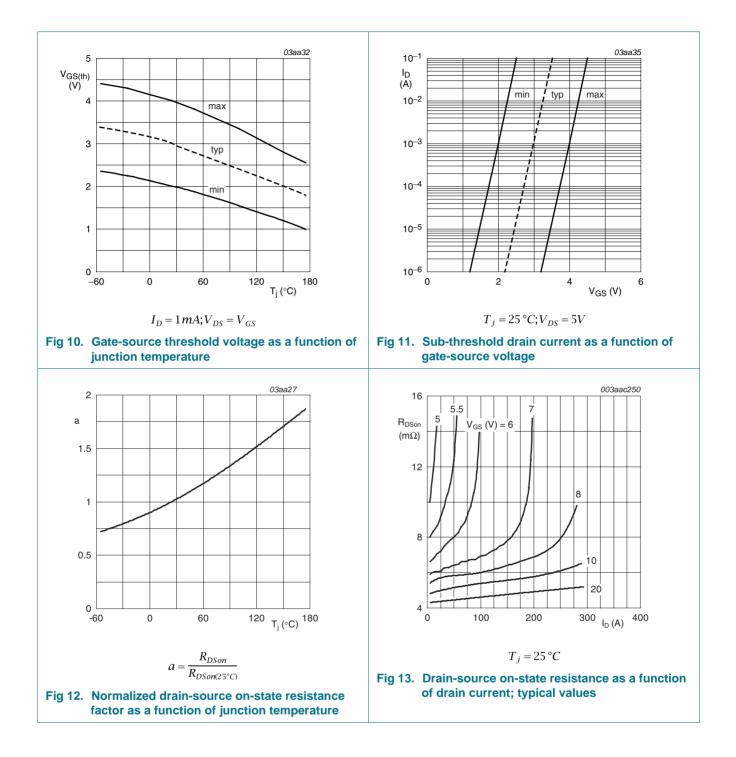
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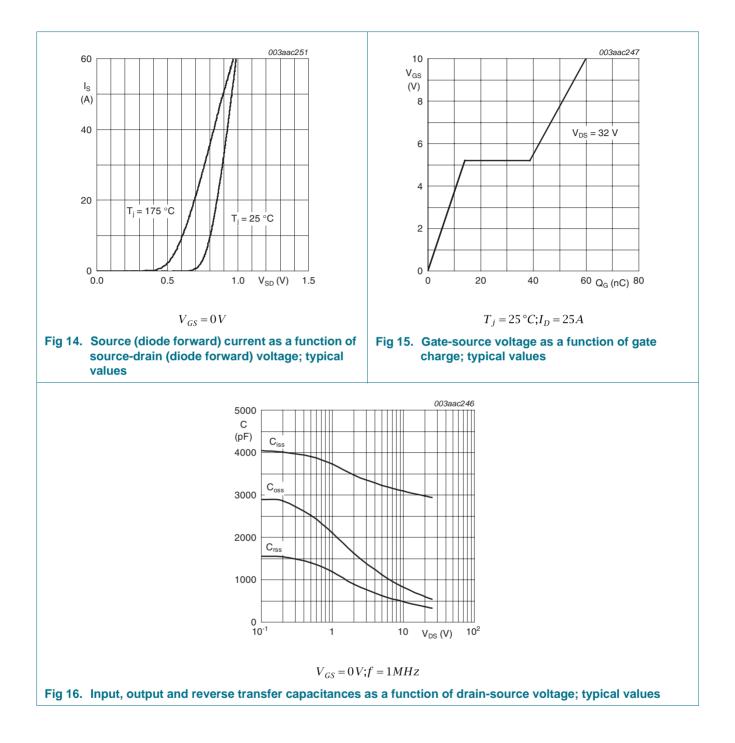
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### 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	40	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	36	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 175 °C; see <u>Figure 10</u>	1	-	-	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; see <u>Figure 10</u>	-	-	4.4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 10</u> ; see <u>Figure 11</u>	2	3	4	V
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = 20 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	2	100	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; see <u>Figure 12</u>	-	-	9.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 12</u> ; see <u>Figure 13</u>	-	4.1	5	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	60	-	nC
Q <sub>GS</sub>	gate-source charge	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 15}{15}$	-	12	-	nC
Q <sub>GD</sub>	gate-drain charge		-	27	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	2870	3820	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 16$	-	540	650	pF
C <sub>rss</sub>	reverse transfer capacitance		-	350	490	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	27	-	ns
t <sub>r</sub>	rise time	R <sub>G(ext)</sub> = 10 Ω; T <sub>j</sub> = 25 °C	-	73	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	82	-	ns
t <sub>f</sub>	fall time		-	63	-	ns
L <sub>D</sub>	internal drain inductance	measured from drain to centre of die; $T_j = 25 \ ^{\circ}C$	-	2.5	-	nH
L <sub>S</sub>	internal source inductance	measured from source lead to source bond pad; $T_j = 25 \text{ °C}$	-	7.5	-	nH
Source-d	rain diode					
V <sub>SD</sub>	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see Figure 14	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ d}I_{S}/\text{d}t = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = -10 \text{ V};$	-	50	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 30 V; T <sub>j</sub> = 25 °C	-	25	-	nC

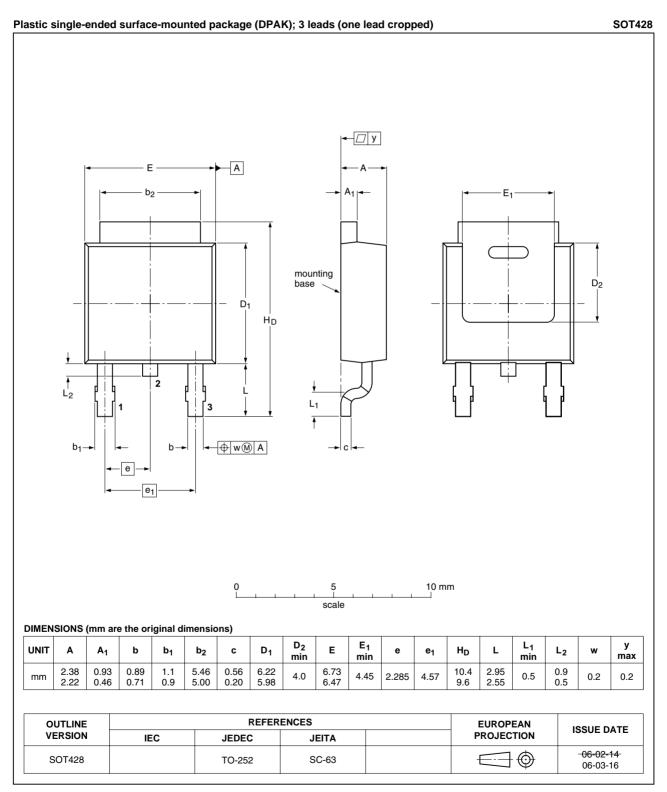






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### 7. Package outline



#### Fig 17. Package outline SOT428 (DPAK)

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## 8. Revision history

Table 7. Revision I	e 7. Revision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes		
BUK725R0-40C_1	20090323	Product data sheet	-	-		

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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